

Search Notes

Application/Control No.

10/813,161

Examiner

James D. Stein

Applicant(s)/Patent under
Reexamination

CARR, CHARLES D.

Art Unit

2874

SEARCHED

Class	Subclass	Date	Examiner
385.	51,88,90 91 and 97	1/24/2006	JDS
216	24	1/24/2006	JDS

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
See attached EAST search history	1/24/2006	JDS
IEEE and INSPEC: optical, alignment, rotate, slide, plate, slab, substrate, bench, etching, tolerance	1/24/2006	JDS
PLUS keyword search	8/15/2005	JDS